

STL9524

AMENDMENTS

- C1
1. (original) An electronic device power testing method, comprising steps of:
 - (a) applying a nominal voltage to an electronic component;
 - (b) introducing a voltage disruption to the nominal voltage;
 - (c) repeating the voltage disruption for a specified number of instances.
 2. (original) The method of claim 1 wherein introducing a voltage disruption comprises applying an increase in voltage.
 3. (original) The method of claim 1 wherein introducing a voltage disruption comprises applying a decrease in voltage.
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- C2
4. (previously amended) The method of claim 1 further comprising applying a sequence of voltages during power-on, wherein a second voltage is activated a specific amount of time after a first voltage was activated.
 5. (previously amended) The method of claim 1 further comprising applying a sequence of voltages during power-off, wherein a second voltage is deactivated a specific amount of time after a first voltage was deactivated.
 6. (previously amended) The method of claim 1 further comprising adjusting a combination of variables selected from the group consisting of voltage disruption frequency, voltage disruption time duration and voltage disruption magnitude.

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C3

7. (original) The method of claim 6 wherein computer software controls the adjusting of selected variables.

C4

8. (Currently Amended) An electronic device power tester, comprising:
- (a) a nominal voltage;
 - (b) circuitry coupled to a power source, the circuitry being configured to produce a voltage disruption disturbance; and
 - (c) a connector that links the circuitry and the nominal voltage to a device.

C5

9. (Currently Amended) The power tester of claim 8 wherein the voltage disruption disturbance is an increase in voltage.

10. (Currently Amended) The power tester of claim 8 wherein the voltage disruption disturbance is a decrease in voltage.

11. (original) The power tester of claim 8 wherein there are multiple power sources that comprise multiple voltage magnitudes.

12. (original) The power tester of claim 11 wherein the circuitry is configured to produce both a decrease and an increase in voltage.

C6

13. (Currently Amended) The power tester of claim 12 further comprising a first connector and a second connector that are linked from the circuitry to two separate devices, the first connector configured for the voltage disruptions disturbances that are due to an increase in voltage and the second connector configured for the voltage disruptions disturbances that are due to a decrease in voltage.

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14. (Currently Amended) The power tester of claim 12 wherein a computer is connected to the power tester and is programmed to allow an operator to specify certain operating parameters of the power tester, including number of voltage disruptions ~~disturbances~~, voltage disruption frequency, voltage disruption time duration, and voltage disruption magnitude.

C7
15. (original) The power tester of claim 11 wherein the circuitry is configured to provide a power on sequence where a first voltage is activated and then, after a specific amount of time from when the first voltage was activated, a second voltage is activated.

16. (original) The power tester of claim 11 wherein the circuitry is configured to provide a power off sequence where a first voltage is deactivated and then, after a specific amount of time from when the first voltage was deactivated, a second voltage is deactivated.

17. (Currently Amended) An electronic device power tester, comprising:
at least one power source;
a connector to connect an electronic device to the power source ~~tester~~;
and
means for generating a voltage disruption ~~disturbance~~ to be delivered to the device via the connector.